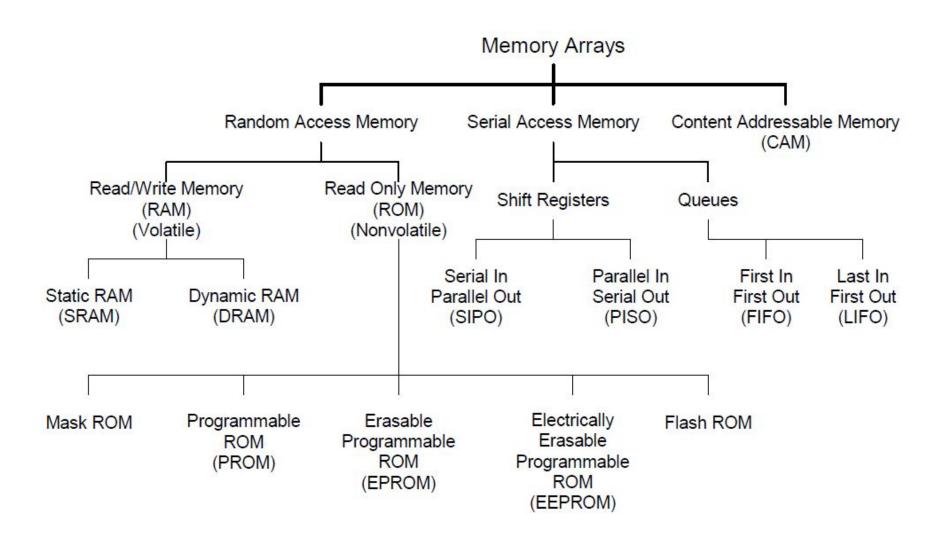
# HSPICE Memory - SRAM

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## **Memory Categories**

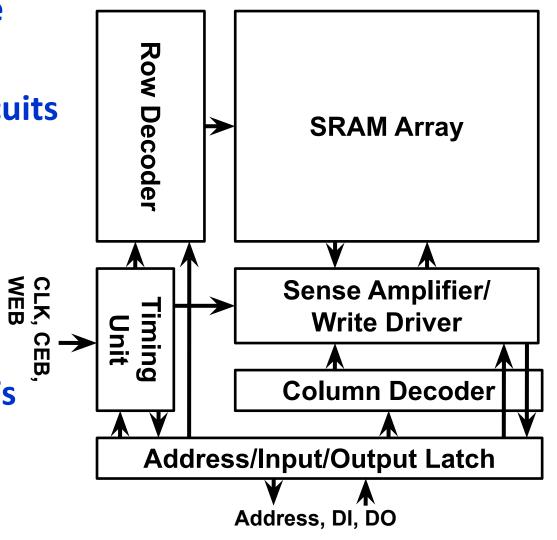


## **Memory Categories**

- RAM: Random Access Memory
  - Historically defined as memory array with individual bit access
- ROM: Read Only Memory
  - Write typically requires high voltages or erasing by UV light
- Volatility vs. Non-volatile of Memory
  - Volatile memory loses data over time or when power is removed (ex:RAM)
  - ◆ Non-volatile memory stores data even when power is removed (ex:ROM)
- Static vs. Dynamic Memory
  - ◆ Static: holds data as long as power is applied (SRAM)
  - Dynamic: must be refreshed periodically (DRAM)

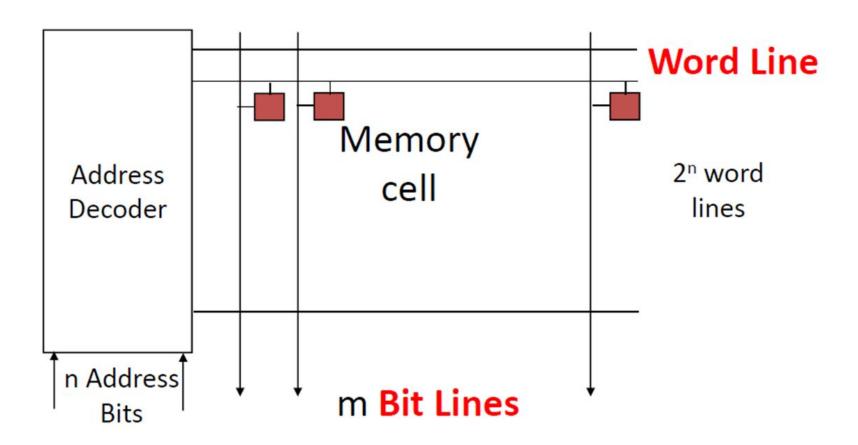
#### **SRAM Architecture**

- SRAM basic structure
  - SRAM Array
- SRAM Peripheral Circuits
  - Sense amplifier
  - Write Driver
  - Row decoder
  - Column decoder
  - Timing unit
- SRAM I/O Latches/FFs
  - ◆ Address Latch
  - Input latch
  - Output latch



# **SRAM Array**

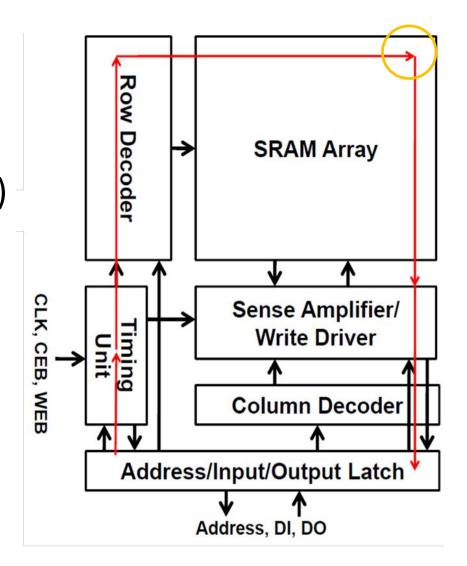
2<sup>n</sup> words of 2<sup>m</sup> bits each



## **Read Operation in Global Circuits**

#### Read Path

- Address latch
- Timing Unit
- Row Decoder (WL driver)
- ◆ SRAM Array
- Selected WL
- Selected BL pairs
- Sense Amplifier
- Output latch



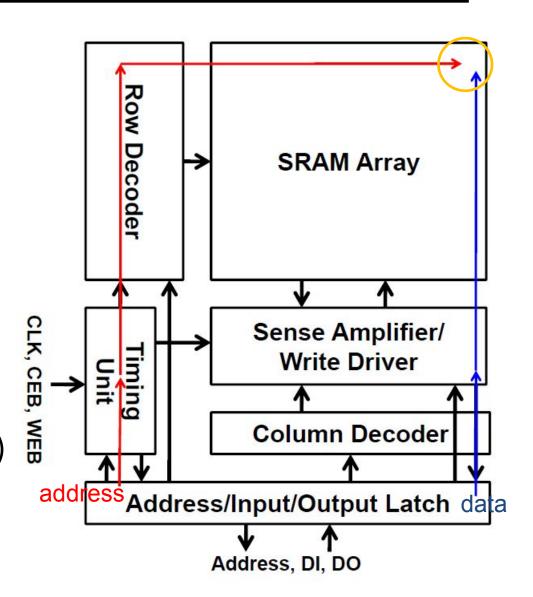
## **Write Operation in Global Circuits**

#### Data Path

- Input latch
- Write Driver
- SRAM Array (Selected BL pairs)

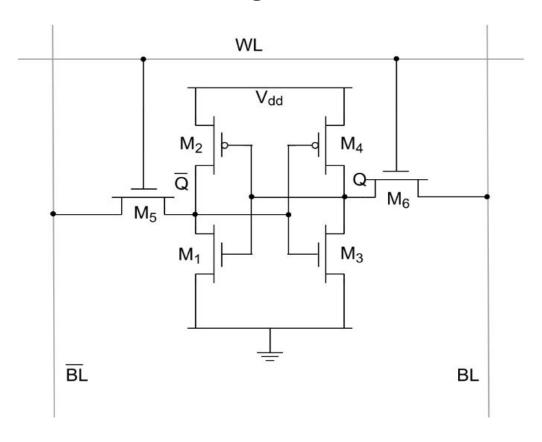
#### Control Path

- Address latch
- Timing Unit
- ◆ SRAM Array (Selected WL)



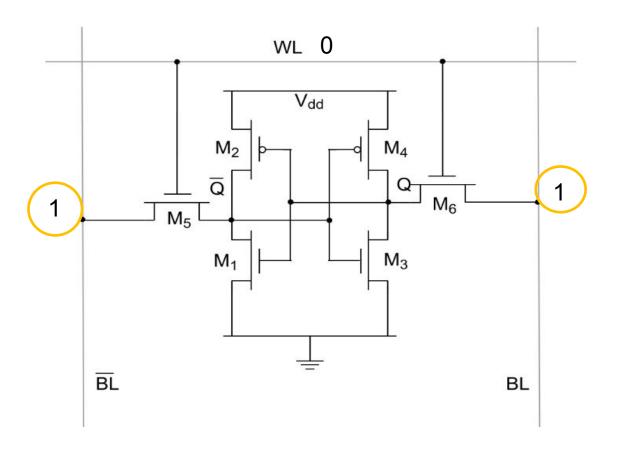
#### **6T SRAM Cell**

- Cross-coupled inverter to latch/store data
- Bi-directional access transistor
  - ♦ "I" NMOS: "strong 0 weak 1" when passing data
    - ... SRAM cell is written through data 0 side.



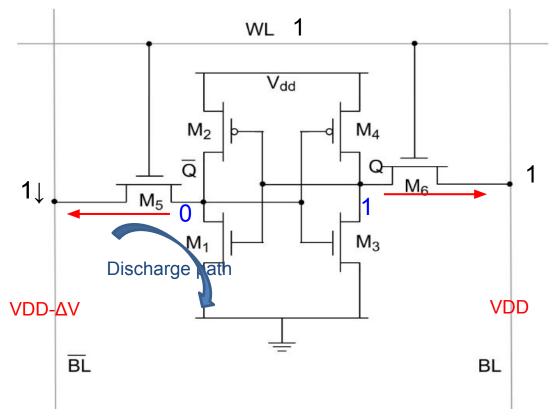
#### **6T SRAM Cell - Hold**

- When power on and no read/write operation command input.
- Bit line & bit line bar is pre-charged, preparing for the command input and do the operations.



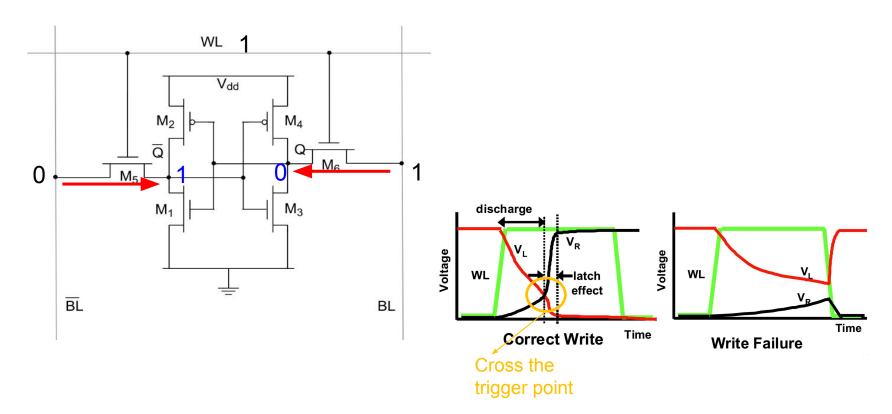
## **6T SRAM Cell - Read**

- Open word line (pull high) and make the pass transistor opened.
- Data (Q & Q bar) influences bit line & bit line bar. The voltage difference on bit line & bit line bar is small and hard to be sensed by ordinary logic gate correctly. To solve the problem, we need sense amplifier at the bottom of array.
- The sensing time in read operation is the critical path of the SRAM because there are many cell on the column and each size of MOS in cells is small.



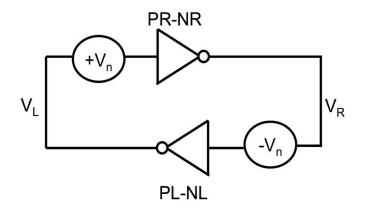
#### **6T SRAM Cell - Write**

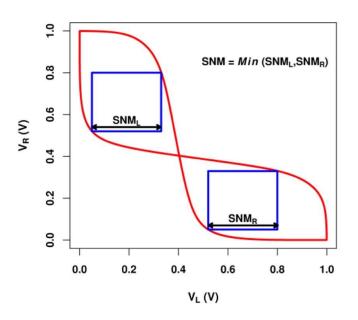
- Write circuit makes bit line & bit line bar transfer to its value.(input 0, input bar 1)
- Open word line and write the value to Q & Q bar.
- Because NMOS pass strong 0 weak 1, the value is written into the cell mainly by "0" side.



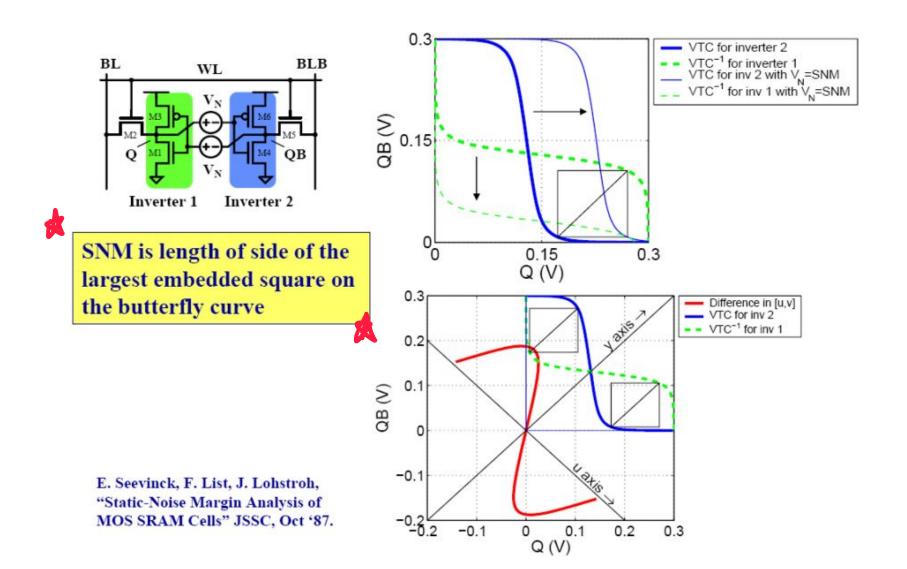
## Static Noise Margin (SNM): Butterfly Curve

- SNM: The maximum value of "Vn" that can be tolerated by the flip-flop before changing state
- Standby (or Retention) SNM: word line low
- Read SNM (RSNM): word line high

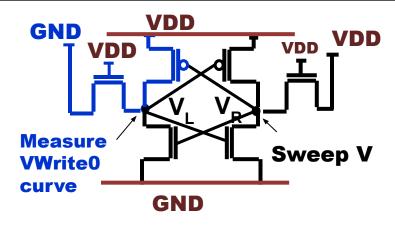


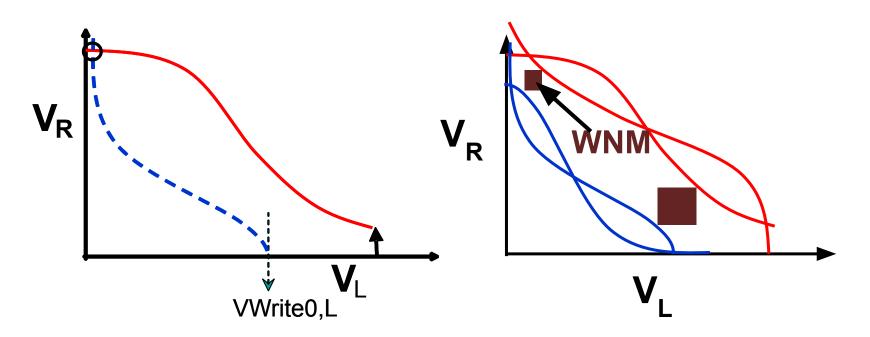


## Static Noise Margin (SNM): Butterfly Curve



# **Write-ability and Write Margin**



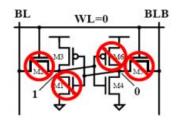


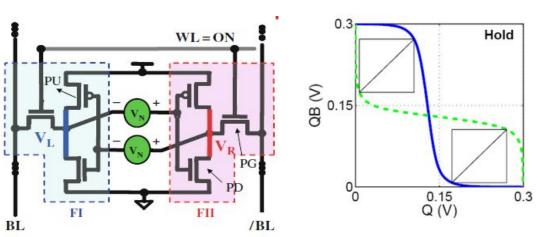
#### **Exercise**

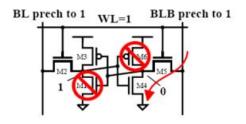
- Using 7nm FinFFT model to design ap 6T SRAM and measure its WM and HSNM and RSNM
- Show the wave form:

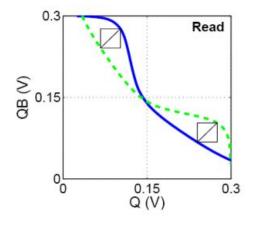
SNM (show signal: v1, v2)

- ☐ Hold SNM
- ☐ Read SNM
- ] Write SNM









Hold Read

# **Exercise Notice**

Elit of voltage.

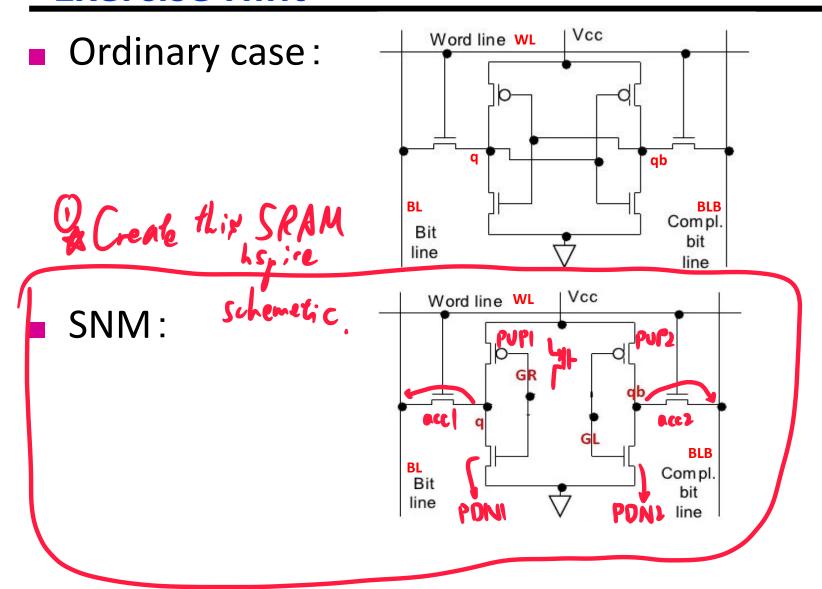
 BL & BLB: I prefer using ".ic" command instead of using ordinary voltage definition because BL & BLB would be floating after pre-charged in the real circuit.

```
.ic V(??.BL) = ?? * ?? need to be edited
.ic V(??.BLB) = ?? * ?? need to be edited
```

 Adding the capacitor on BL & BLB is to make the simulation closer to reality. (if the wave form is weird you can adjust by yourself)

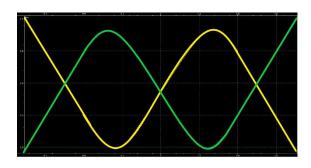
CBLB BLB GND BITCAP

## **Exercise Hint**

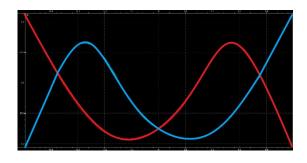


## **Exercise SNM Wave Form Hint**

Hold SNM wave form:



Read SNM wave form:



Write SNM wave form:

